



Small Thin Gap Chamber High Voltage Investigation for the New Small Wheels

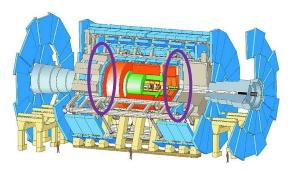
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08/08/2024

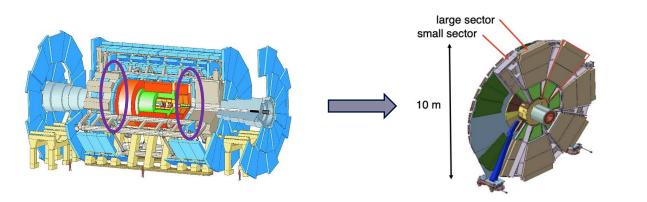
Overview

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- 4. Side A and C comparison
- 5. Current data investigation: Building a database
- 6. Cumulative charge measurements: Ageing test comparisons
- 7. Other activities: Hardware and operations
- 8. Challenges and next steps
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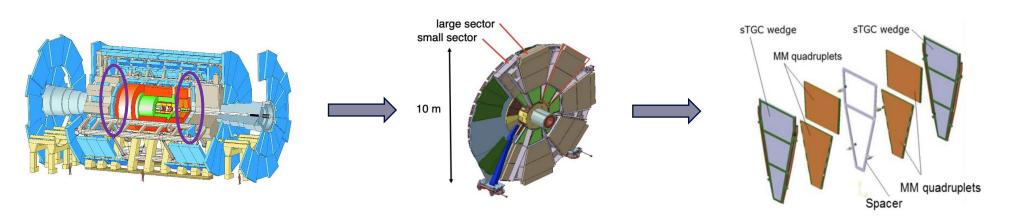




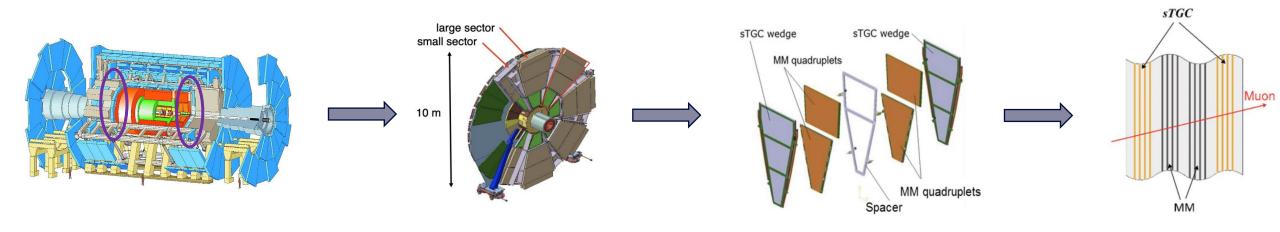




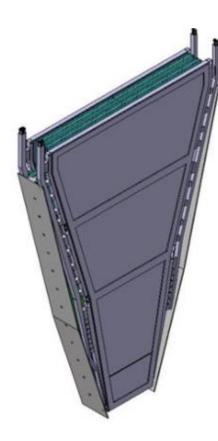




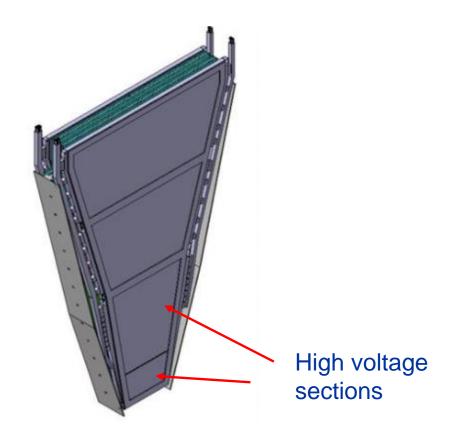




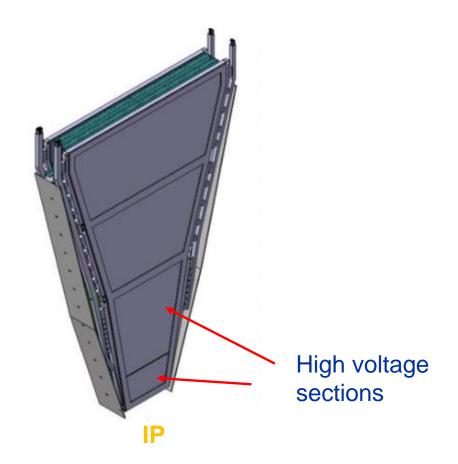




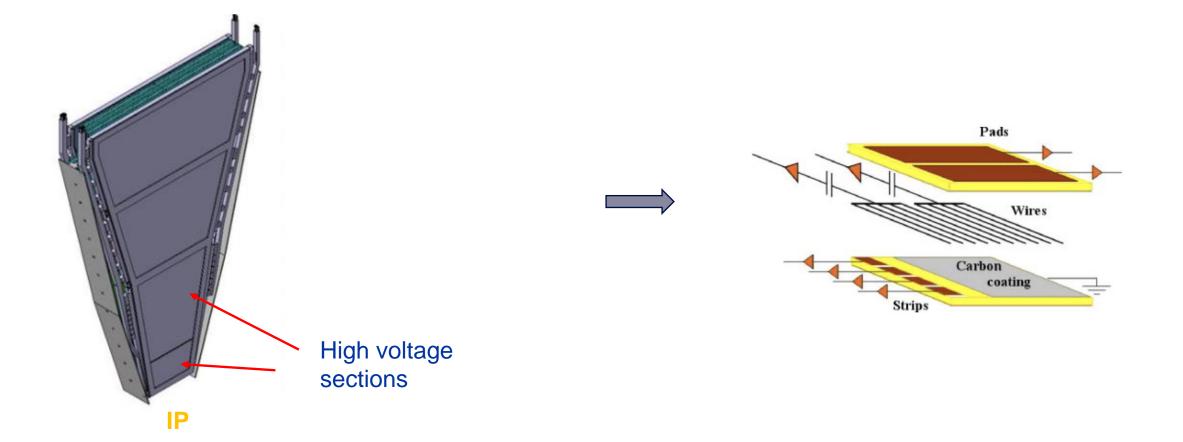














Project Motivation

Problem

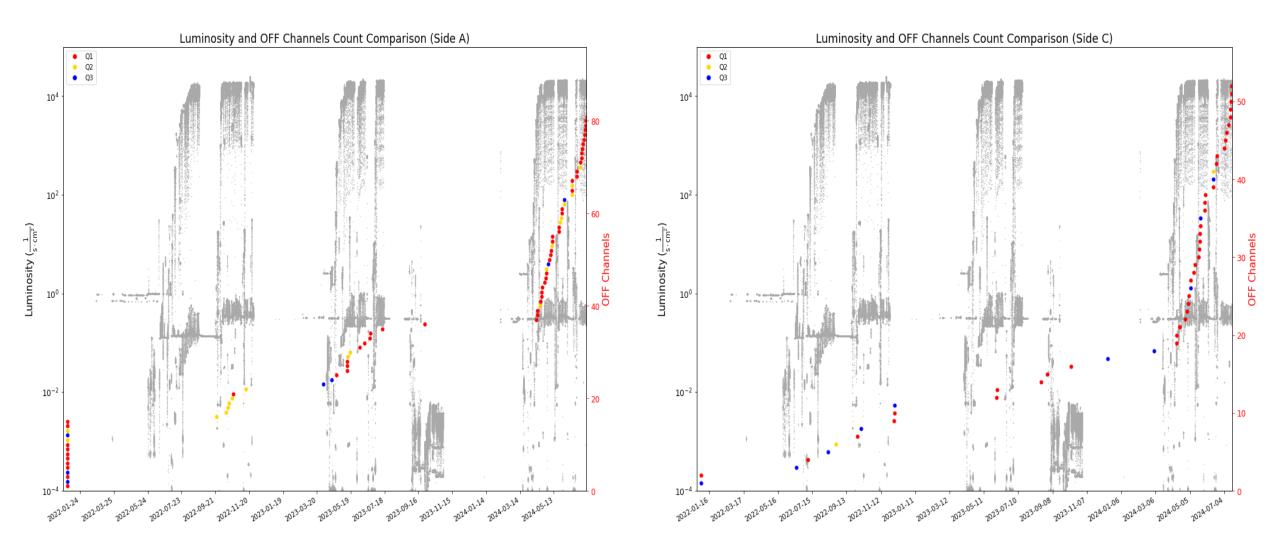
- The Small Thin Gap Chambers (sTGC) in the New Small Wheel (NSW) are failing/dying at a fast rate
 - This is evident in spikes in current, dead channels, etc.
 - This affects data taking, reliability and overall efficiency of the detector

Goal

- Visualize the problem
- Find any patterns that might clue us towards what is happening within these chambers
- Build a database of current data for failed channels

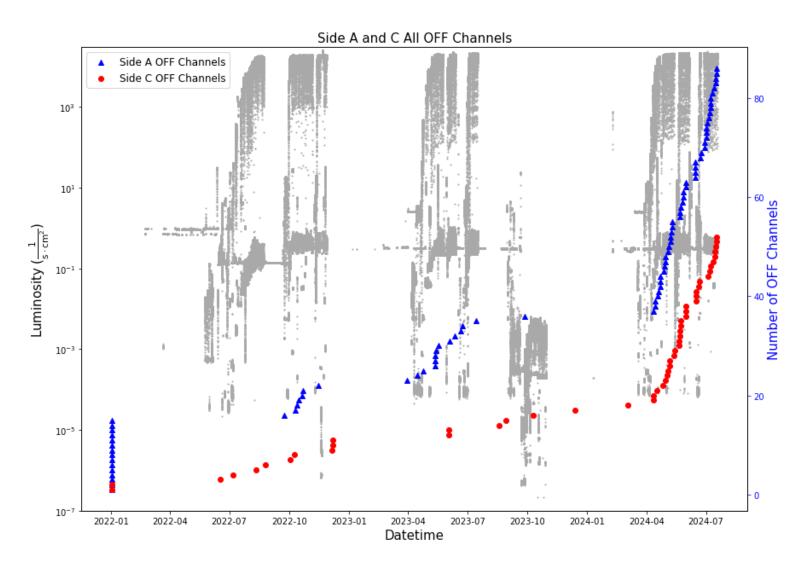


OFF Channels and Luminosity



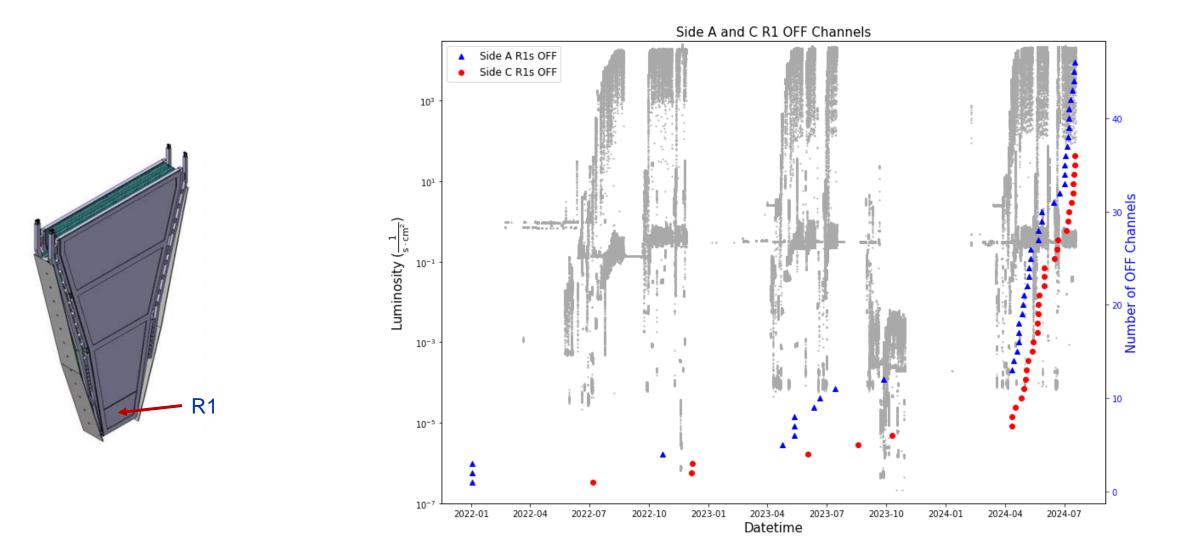
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Side A and C Comparison





Side A and C Comparison



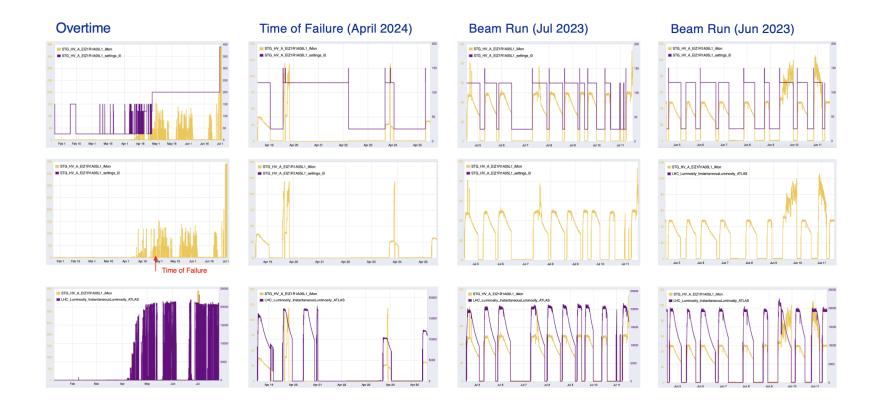


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Current Spikes for Individual Channels

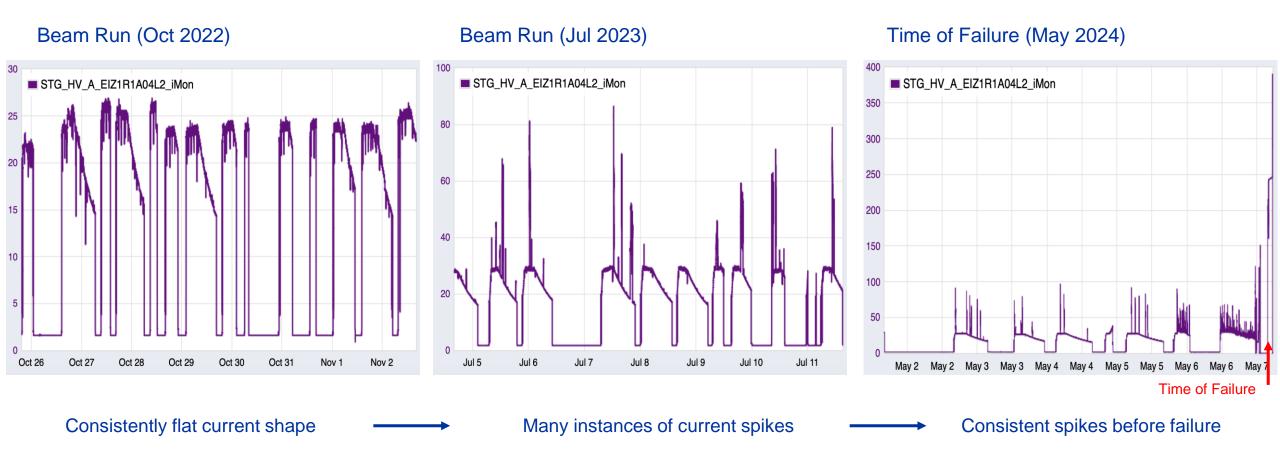
Building up a database for OFF channels

- Look at current data for each OFF channel within a week of failure and for two beam runs prior to failure
- Current behavior can tell us what is happening in the detector





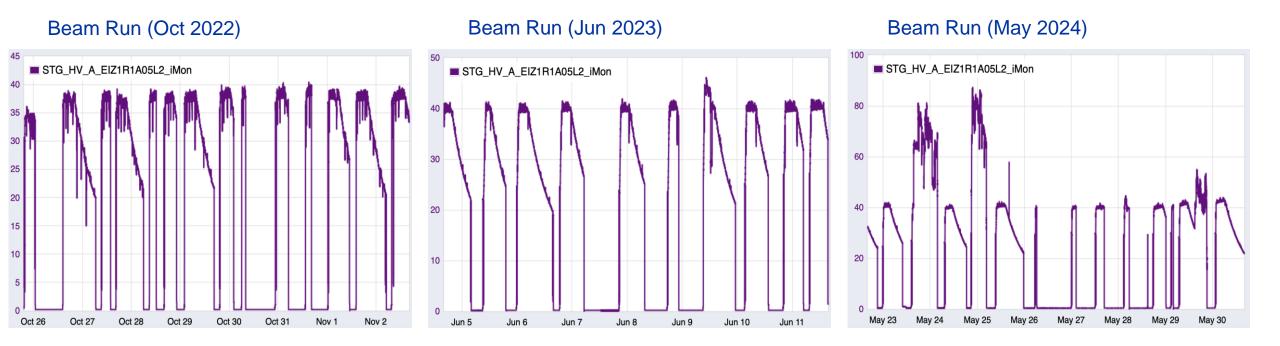
Current Pattern Example: OFF Channel



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Current Pattern Example: Good Channel





Other Hardware/Operations Activities



ATLAS Control Room



ATLAS Cavern





Current Patterns

- 1. Understanding how current spikes progress and we approach time of failure can help us make predictions about currently good channels
- 2. Taking a closer look helps us to understand the type of error we are seeing (burning, graphite coming off, etc.)

Visualizing the trend in OFF channels

- 1. Failure of channels seems to be correlated with operation is luminosity a cause?
- 2. The significant difference in number of channels OFF between sides is explained by the numerous failed channels at the beginning of 2022
- 3. Side A and C are likely experiencing the same issue due to their similar behavior, despite previous beliefs that side A was experiencing more problems due to increased background

Future Work

- 1. Ageing Test
- 2. Accumulated charge measurements
- 3. Efficiency Scans



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